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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
APPLICATION NO.	FILING DATE	TRST NAMED INVENTOR	ATTORUSE DOCUMENTOS	
10/801,944	03/15/2004	John T. Strom	044182 308760	2939
7590 08/15/2005			EXAMINER	
Pillsbury Winthrop LLP			KIM, PAUL L	
Intellectual Property Group				DADER AND ADER
Suite 200			ART UNIT	PAPER NUMBER
11682 El Camir		2857		
San Diego, CA 92130-2092			DATE MAILED: 08/15/2005	

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)			
	10/801,944	STROM ET AL.			
Office Action Summary	Examiner	Art Unit			
	Paul Kim	2857			
The MAILING DATE of this communication app Period for Reply	pears on the cover sheet with the c	orrespondence address			
A SHORTENED STATUTORY PERIOD FOR REPL' THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.1 after SIX (6) MONTHS from the mailing date of this communication. - If the period for reply specified above is less than thirty (30) days, a repl - If NO period for reply is specified above, the maximum statutory period of Failure to reply within the set or extended period for reply will, by statute Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	36(a). In no event, however, may a reply be time within the statutory minimum of thirty (30) days will apply and will expire SIX (6) MONTHS from a cause the application to become ABANDONE	nely filed s will be considered timely. the mailing date of this communication. D (35 U.S.C. § 133).			
Status					
1) Responsive to communication(s) filed on 19 Ju	uly 2004.				
	action is non-final.				
3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is					
closed in accordance with the practice under Ex parte Quayle, 1935 C.D. 11, 453 O.G. 213.					
Disposition of Claims		·			
4) ⊠ Claim(s) <u>1-20</u> is/are pending in the application 4a) Of the above claim(s) is/are withdray 5) □ Claim(s) is/are allowed. 6) ⊠ Claim(s) <u>1-4,6,7,9-13,15,16 and 18-20</u> is/are ref. 7) ⊠ Claim(s) <u>5,8,14 and 17</u> is/are objected to. 8) □ Claim(s) are subject to restriction and/or	wn from consideration.				
Application Papers					
9) The specification is objected to by the Examine 10) The drawing(s) filed on is/are: a) acc Applicant may not request that any objection to the Replacement drawing sheet(s) including the correct 11) The oath or declaration is objected to by the Example 11.	epted or b) objected to by the Idrawing(s) be held in abeyance. See tion is required if the drawing(s) is obj	e 37 CFR 1.85(a). jected to. See 37 CFR 1.121(d).			
Priority under 35 U.S.C. § 119	,				
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority document 2. Certified copies of the priority document 3. Copies of the certified copies of the priority document application from the International Bureau * See the attached detailed Office action for a list	s have been received. s have been received in Applicati rity documents have been receive u (PCT Rule 17.2(a)).	on No ed in this National Stage			
Attachment(s) 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date	4) Interview Summary Paper No(s)/Mail Da 5) Notice of Informal P 6) Other:				

DETAILED ACTION

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

2. Claims 1-4, 6, 7, 9-13, 15, 16, and 18-20 are rejected under 35 U.S.C. 102(e) as being anticipated by Harris.

With regard to claims 1 and 9, Harris teaches a method of calculating and measuring a probe float comprising: acquiring a free-hanging planarity measurement, obtaining a first electrical contact planarity measurement, and calculating probe float using results of the acquiring and obtaining (abstract).

With regard to claims 2 and 10, Harris teaches the calculating comprising computing a difference between results of the obtaining and acquiring (col. 5, lines 38-42).

With regard to claims 3 and 12, Harris teaches acquiring a reference planarity measurement, providing relative translation between a contact surface and a probe card, identifying new free-hanging probes responsive to the providing, assigning a planarity value to newly identified free-hanging probes, and selectively repeating the providing, identifying, and assigning (col. 5, lines 1-20 & col. 6, lines 42-56).

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With regard to claims 4 and 13, Harris teaches selectively iterating the providing, identifying, and assigning until a planarity value has been assigned to every probe (col. 11, lines 42-46).

With regard to claims 6, 7, 15, and 16, Harris teaches acquiring a reference planarity and identifying new free-hanging probes measurement comprises utilizing the optical system (col. 6, lines 32-37).

With regard to claim 11, Harris teaches repeating the acquiring, obtaining, and calculating for each probe (fig. 3).

With regard to claim 18, Harris teaches a computer readable medium with data and instructions that acquires a free-hanging measurement, obtains a first electrical contact planarity measurement, and calculates probe float using the free-hanging planarity measurement and the first electrical contact planarity measurement (abstract & col. 11, lines 32-40).

With regard to claim 19, Harris teaches the instructions further comprising computing a difference between results of the obtaining and acquiring (col. 5, lines 38-42).

With regard to claim 20, Harris teaches the instructions further comprising repeating the acquiring, obtaining, and calculating for each probe (fig. 3).

Allowable Subject Matter

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3. Claims 5, 8, 14, and 17 are objected to as being dependent upon a rejected base

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claim, but would be allowable if rewritten in independent form including all of the

limitations of the base claim and any intervening claims.

Conclusion

4. The prior art made of record and not relied upon is considered pertinent to

applicant's disclosure. Hershel et al, Lee et al, and Reid et al all teach a method of

analyzing a probe card.

5. Any inquiry concerning this communication or earlier communications from the

examiner should be directed to Paul Kim whose telephone number is 571-272-2217.

The examiner can normally be reached on Monday-Thursday 10:00-6:30.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, Marc Hoff can be reached on 571-272-2216. The fax phone numbers for the

organization where this application or proceeding is assigned are 571-273-8300 for

regular communications and for After Final communications.

Any inquiry of a general nature or relating to the status of this application or

proceeding should be directed to the receptionist whose telephone number is 703-308-

0956.

PK

August 4, 2005

MARC S. HOFF

TECHNOLOGY CENTER 2800